

Notice of References Cited	Application/Control No. 10/019,201	Applicant(s)/Patent Under Reexamination MAENO ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6417532 - B2	07-2002	Tsunoda et al.	257/219
	B	US-6353258 - B1	03-2002	Inoue et al.	257/723
	C	US-6297549 - B1	10-2001	Hiyoshi	257/703
	D	US-6272015 - B1	08-2001	Mangtani	361/707
	E	US-6215679 - B1	04-2001	Yamane et al.	363/132
	F	US-5926372 - A	07-1999	Rinehart et al.	361/704
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP - 2001237369 - A	08-2001	Japan	Polack et al.	---
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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